

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/643,117	BAW, ALLAN		
Examiner	Art Unit		
Frank Duong	2616		

SEARCHED					
Class	Subclass	Date	Examiner		
· · · · · · · · · · · · · · · · · · ·					
-					

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
į			·		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST SEARCH (see printout)	4/20/2007	FD		
INVENTORSHIP SEARCH (see printout)	4/20/2007	FD		
IEEE/INTERNET SEARCH	4/20/2007	FD		